

INFORMATION DISCLOSURE CITATION
(Use several sheets if necessary)

Docket Number (Optional)
16791 (03006)

Application Number
Unassigned

Applicant(s)
Alistair C.H. Rowe, et al.

Filing Date
Herewith

Group Art Unit
Unassigned

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
OD		5,663,507	09/02/97	Westervelt, et al.			

FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

OD		T. Zhou, et al.; "Extraordinary magnetoresistance in externally shunted van der Pauw plates"; <u>Applied Physics Letters</u> ; Vol. 78; No. 5; pp. 667-69; (2001)
OD		S.A. Solin, et al.; "Nonmagnetic semiconductors as read-head sensors for ultra-high-density magnetic recording"; <u>Applied Physics Letters</u> ; Vol. 80; No. 21; pp. 4012-14; (2002)
OD		A.C.H. Rowe, et al.; "A uniaxial tensile stress apparatus for temperature-dependent magnetotransport and optical studies of thin films"; <u>Review of Scientific Instruments</u> ; Vol. 73; No. 12; pp. 4270-76; (2002)
OD		S.A. Solin, et al.; "Enhanced Room-Temperature Geometric Magnetoresistance in Inhomogeneous Narrow-Gap Semiconductors"; <u>Science</u> ; Vol. 289; pp. 1530-32; (2000)

EXAMINER

Octavia Davis

DATE CONSIDERED

10/21/04

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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DS	C.A. Mead, et al.; "Fermi Level Position at Metal-Semiconductor Interfaces"; <u>Physical Review</u> ; Vol. 134; No. 3A; pp. A713-16; (1964)
DS	G. Margaritondo; "Interface states at semiconductor junctions"; <u>Rep. Prog. Phys.</u> ; Vol. 62; pp. 7650-808; (1999)
DS	C.S. Gworek, et al.; "Pressure dependence of Cu, Ag, and Fe/n-GaAs Schottky barrier heights"; <u>Phy. Rev.B</u> ; Vol. 64; pp. 045322-1 - 6; (2001)
DS	Peter Van Vessel et al.; "Rediscovering the Strain Gauge Pressure Sensor"; <u>Sensors</u> ; 8 pps.; (1999)

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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)		
DS		Adhesives List printed from www.tokyosokki.co.jp/e/product . . . ; on 6/27/2003
DS		Fujidura Semiconductor Pressure Sensors printed from www.fujidura.co.jp/sensor/press/intro . . . " on 6/27/2003
DS		Y. Ohmura; "Piezoresistance Effect in p-Type Semiconductors Si and Ge"; 21 st International Conference on The Physics of Semiconductors; Vol. 1; pp. 273-76; (1992

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